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**Ralf Widenhorn
Antoine Dupret**
Editors

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P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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and

IS&T—The Society for Imaging Science and Technology

7003 Kilworth Lane, Springfield, Virginia, 22151 USA

Telephone +1 703 642 9090 (Eastern Time) · Fax +1 703 642 9094

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The CID Number appears on each page of the manuscript. The complete citation is used on the first page, and an abbreviated version on subsequent pages.

Contents

v *Authors*
vii *Conference Committee*

SESSION 1 HIGH-PERFORMANCE SENSORS

- 9403 02 **2.2 μ m BSI CMOS image sensor with two layer photo-detector (Best Paper Award)** [9403-1]
- 9403 03 **A compact THz imaging system** [9403-2]
- 9403 04 **Signal conditioning circuits for 3D-integrated burst image sensors with on-chip A/D conversion** [9403-3]
- 9403 05 **A 4MP high-dynamic-range, low-noise CMOS image sensor** [9403-4]
- 9403 06 **Multi-camera synchronization core implemented on USB3 based FPGA platform (Best Paper Award)** [9403-5]

SESSION 2 SENSORS, COLOR, AND SPECTROSCOPY

- 9403 07 **Compressed hyperspectral sensing** [9403-6]
- 9403 08 **Acousto-optic imaging with a smart-pixels sensor** [9403-29]
- 9403 0A **Design, fabrication and characterization of a polarization-sensitive focal plane array** [9403-9]
- 9403 0B **High dynamic, spectral, and polarized natural light environment acquisition** [9403-10]
- 9403 0C **A high-sensitivity 2x2 multi-aperture color camera based on selective averaging** [9403-11]

SESSION 3 SENSOR PERFORMANCE AND MODELING

- 9403 0E **Analysis of pixel gain and linearity of CMOS image sensor using floating capacitor load readout operation** [9403-13]
- 9403 0F **Addressing challenges of modulation transfer function measurement with fisheye lens cameras** [9403-14]

SESSION 4 SMART SENSORS

- 9403 OI **A SPAD-based 3D imager with in-pixel TDC for 145ps-accuracy ToF measurement** [9403-17]
- 9403 OJ **Neuro-inspired smart image sensor: analog Hmax implementation** [9403-18]
- 9403 OK **A 12-bit 500KSPS cyclic ADC for CMOS image sensor** [9403-19]
- 9403 OL **14-bit pipeline-SAR ADC for image sensor readout circuits** [9403-20]

SESSION 5 NOISE

- 9403 OM **Power noise rejection and device noise analysis at the reference level of ramp ADC** [9403-21]
- 9403 ON **The effect of photodiode shape on dark current for MOS imagers** [9403-22]
- 9403 OO **High-speed binary CMOS image sensor using a high-responsivity MOSFET-type photodetector** [9403-23]
- 9403 OP **Design considerations for a low-noise CMOS image sensor** [9403-24]

INTERACTIVE PAPER SESSION

- 9403 OR **Short wave infrared hyperspectral imaging for recovered post-consumer single and mixed polymers characterization** [9403-26]
- 9403 OS **Designing and construction of a prototype of (GEM) detector for 2D medical imaging application** [9403-27]
- 9403 OT **Enhanced correction methods for high density hot pixel defects in digital imagers** [9403-28]

Authors

Numbers in the index correspond to the last two digits of the six-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first four digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Ahn, Peter, 0M
Alanazi, Mohammed S., 0S
Aldosary, Abdullah F., 0S
Alghamdi, Abdulrahman S., 0S
Asami, T., 02
Bae, Myunghan, 0O
Barjean, K., 08
Bonifazi, Giuseppe, 0R
Bonnard, R., 04
Callet, Patrick, 0B
Carmona-Galán, R., 0I
Chang, Yuchun, 05, 0K, 0L
Chapman, Glenn H., 0T
Charlet, Alexandre, 0P
Cho, KwangJun, 0M
Choi, Byoung-Soo, 0O
Choi, EunJung, 0M
Choi, Pyung, 0O
Contreras, K., 08
Deegan, Brian M., 0F
Denny, Patrick E., 0F
Dever, Barry, 0F
Dias, Morgado, 06
Ding, Ning, 0L
Domínguez-Castro, Rafael, 0P
Dubois, Jérôme, 0J
Dunne, Bruce E., 0N
Eda, K., 02
Egawa, Y., 02
Ettori, D., 08
Fuchs, Philippe, 0B
González-Márquez, Ana, 0P
Gou, JaSeung, 0M
Guellec, F., 04
Hasumi, R., 02
Honda, K., 02
Jiao, Lihong, 0N
Jiménez-Garrido, Francisco, 0P
Jo, Sung-Hyun, 0O
Kagawa, Keiichiro, 0C
Kawahito, Shoji, 0C
Koren, Israel, 0T
Koren, Zahava, 0T
Kuroda, R., 0E
Kusuhara, F., 0E
Laudereau, J.-B., 08
Li, Jing, 05
Li, Zhaohan, 0K
Liu, Tianzhao, 0L
Liu, Yang, 05
Ma, Cheng, 05, 0K, 0L
Maghrabi, A. H., 0S
Medeiro, Fernando, 0P
Mochizuki, A., 02
Momose, H. S., 02
Muller, Thomas, 0B
Musa, Purnawarman, 0J
Ninkov, Zoran, 0A
Ohguro, T., 02
Ootani, H., 02
Paindavoine, Michel, 0J
Palmieri, Roberta, 0R
Park, HyunMook, 0M
Peng, Can, 0L
Peng, Leli, 0K
Porral, Philippe, 0B
Ramaz, F., 08
Rodríguez-Vázquez, Angel, 0I, 0P
Russell, Laura, 0F
Sandré-Chardonnal, Etienne, 0B
Santos, Pedro, 06
Sasaki, H., 02
Segura Puchades, J., 04
Seo, KangBong, 0M
Seo, Min-Woong, 0C
Serranti, Silvia, 0R
Sešek, Aleksander, 03
Shin, Jang-Kyoo, 0O
Sousa, Ricardo M., 06
Sugawa, S., 0E
Sugiura, Y., 02
Švigelj, Andrej, 03
Takasawa, Taishi, 0C
Taylor, Steven, 0N
Thomas, Rahul, 0T
Thomas, Rohit, 0T
Tinet, E., 08
Toyoshima, Y., 02
Trontelj, Janez, 03
Tsagakatakis, Grigorios, 07
Tsakalides, Panagiotis, 07
Tualle, J.-M., 08
Uhring, Pr. W., 04
Um, JiYong, 0M
Villegas, Alberto, 0P
Vornicu, I., 0I
Vorobiev, Dmitry, 0A
Wakashima, S., 0E

Wang, Gengyun, 0K, 0L
Wang, Xinyang, 05
Wäny, Martin, 06
Yamashita, H., 02
Yasutomi, Keita, 0C
Yoo, SangDong, 0M
Zhang, Bo, 0C
Zhou, Quan, 05
Zlokolica, Vladimir, 0F

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- 1 High-Performance Sensors
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- 3 Sensor Performance and Modeling
Jean-Michel Tualle, Université Paris 13 (France)

- 4 Smart Sensors
Antoine Dupret, Commissariat à l'Énergie Atomique (France)
- 5 Noise
Rihito Kuroda, Tohoku University (Japan)
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